



SBND Electronics Data Analysis

Adrian Orea, FNAL SIST Intern

Supervisor: Minerba Betancourt

UIUC Mechanical Engineering

3 August 2018



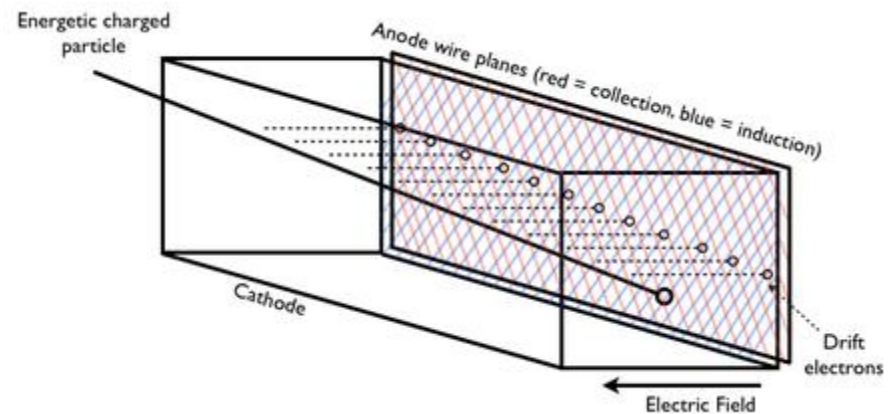
Outline

- Objective
- Background
 - LArTPC and test beam
 - Purity
- Purity Calculation
- Multi-Channel FFT and Waveform plotting framework
- Noise RMS Analysis
- Raw Digit Event Display
- Future work
- Conclusion

LArTPC

- Time Projection Chamber (TPC)
 - Filled with Liquid Argon
 - Two Planes
 - Collection and Induction
 - High electric field
 - Used at several detectors
 - SBND, MicroBooNE, Icarus, and DUNE

1



TPC at Fermilab Test Beam Facility (FTBF)

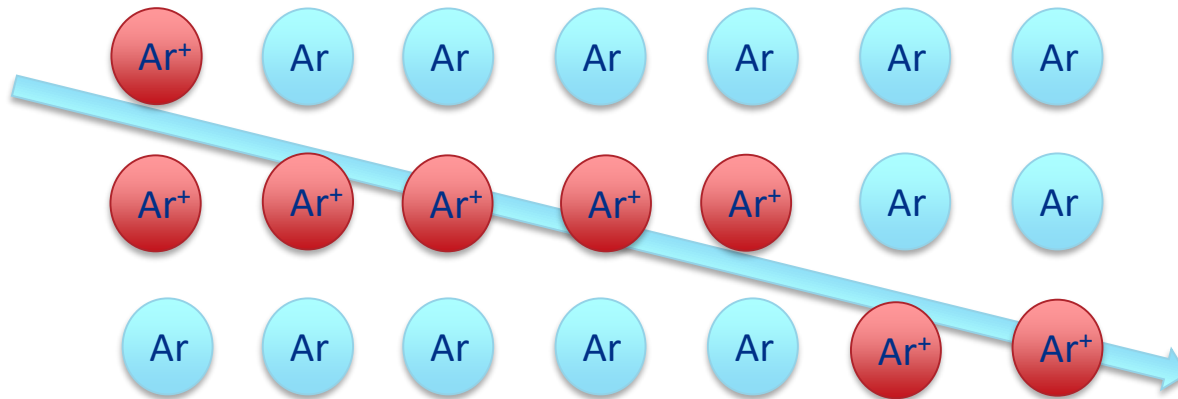
- FTBF used to test detectors with a beam of protons
 - Beam for this project was a mixture of protons, pions, and kaons
- Beam is pulsed
 - SBND TPC placed in Cryostat
 - Boards and wiring secured
- Data was collected for several days at a time
 - Cosmic muon data could also be collected





Purity Calculation

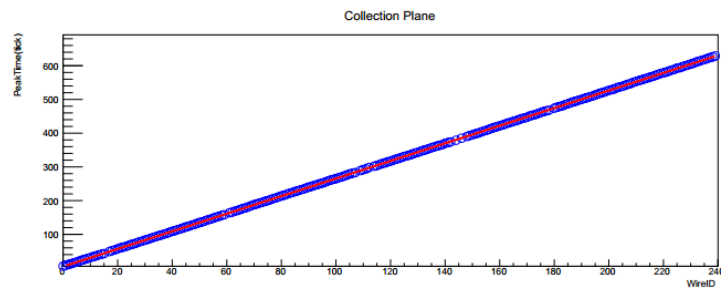
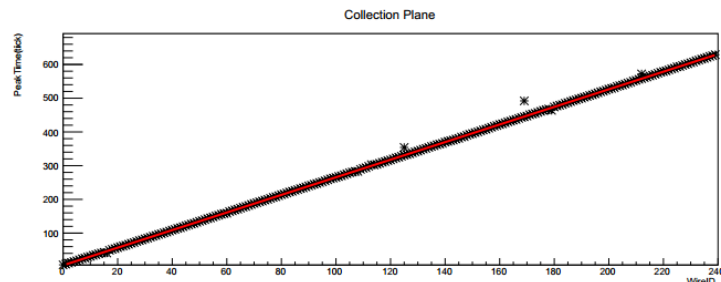
- Free electrons can easily travel through liquid Argon
 - Some get recaptured by Argon Ions
- Although a tank of pure Argon is ideal, it's not
 - Potential contamination during various filling and boiling phases
 - Innate contamination from source
- Electronegative contaminants capture free electrons
 - Oxygen, water, etc



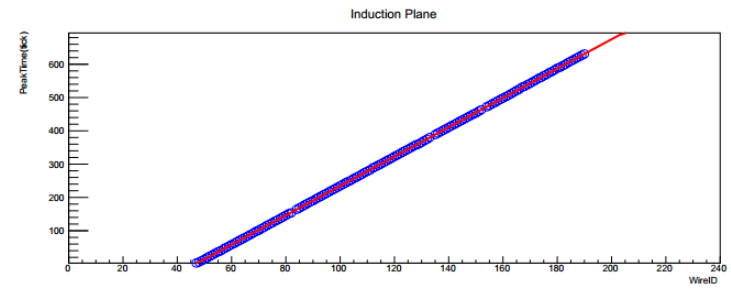
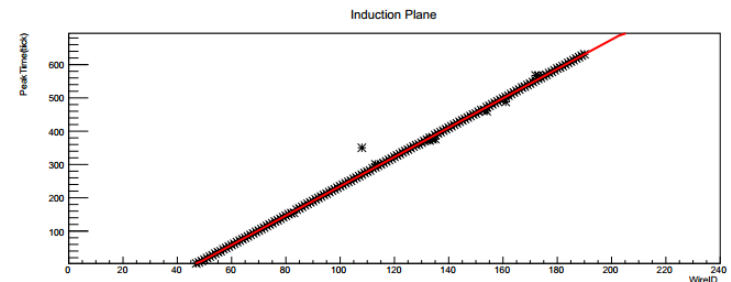
Purity Calculation

- Apply first cut on number of hits and unique wire numbers
 - Plot Peaktime vs wire number, acts as a track reconstruction
 - Induction and collection planes
 - Remove points farther than 2 ticks from fit line

Collection Plane

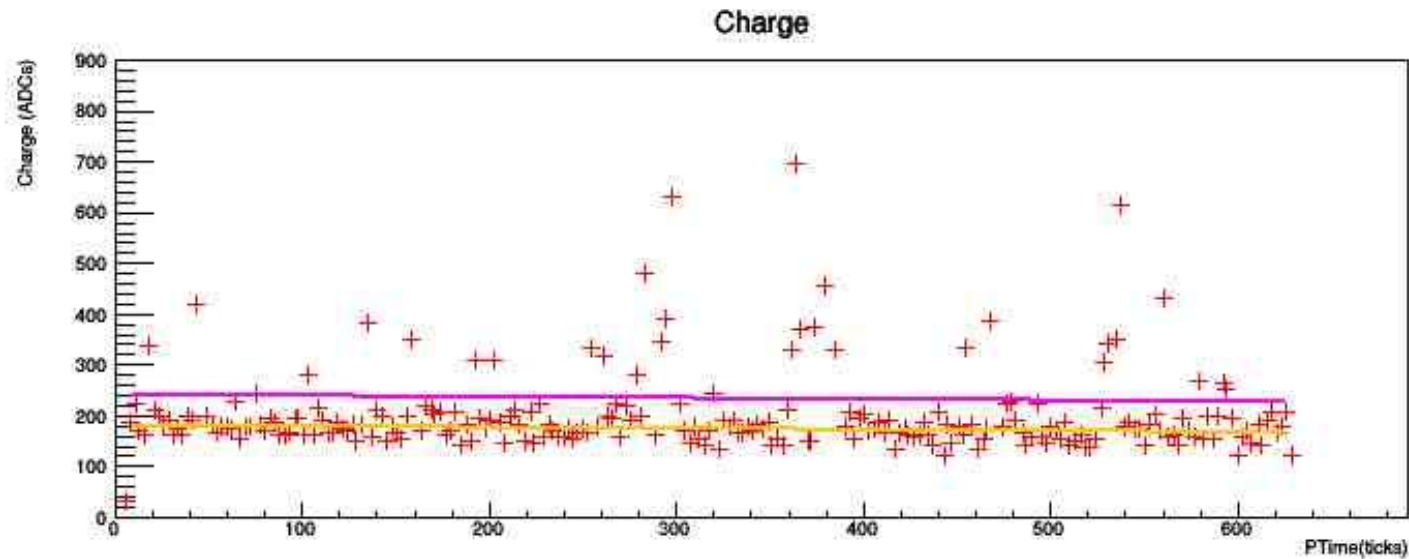


Induction Plane



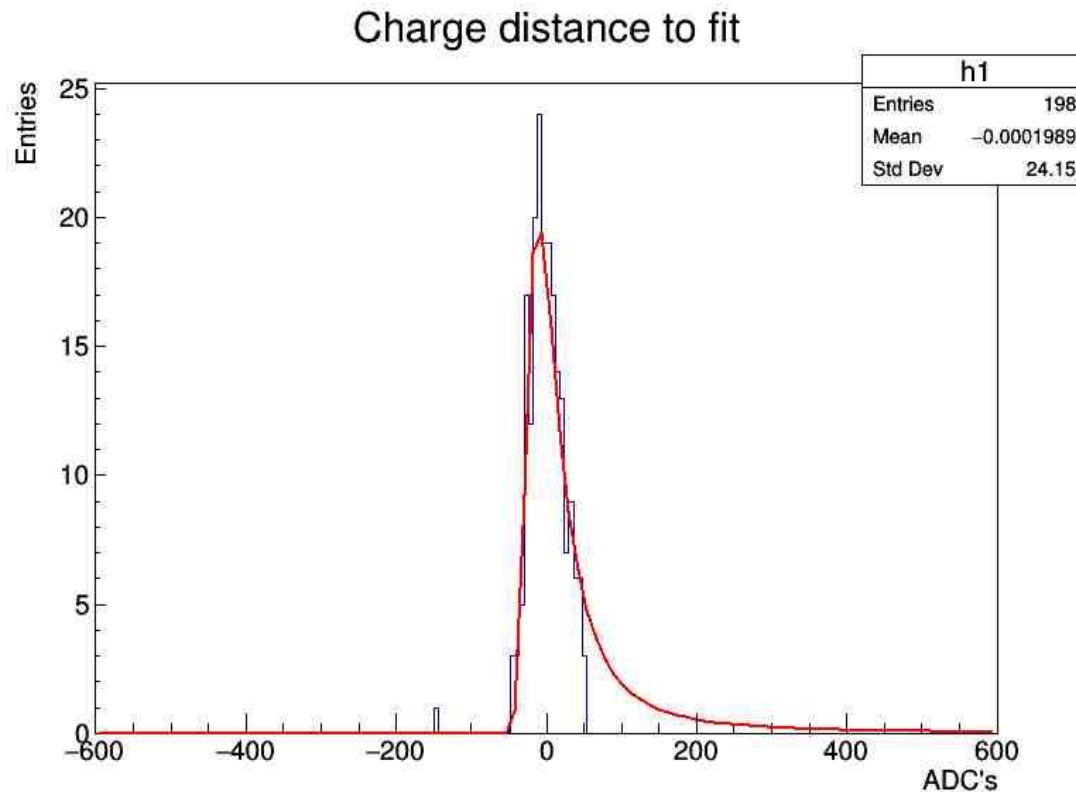
Purity Calculation cont.

- Plot integral (charge) vs peak time
 - Fit with exponential, normalized based on geometry



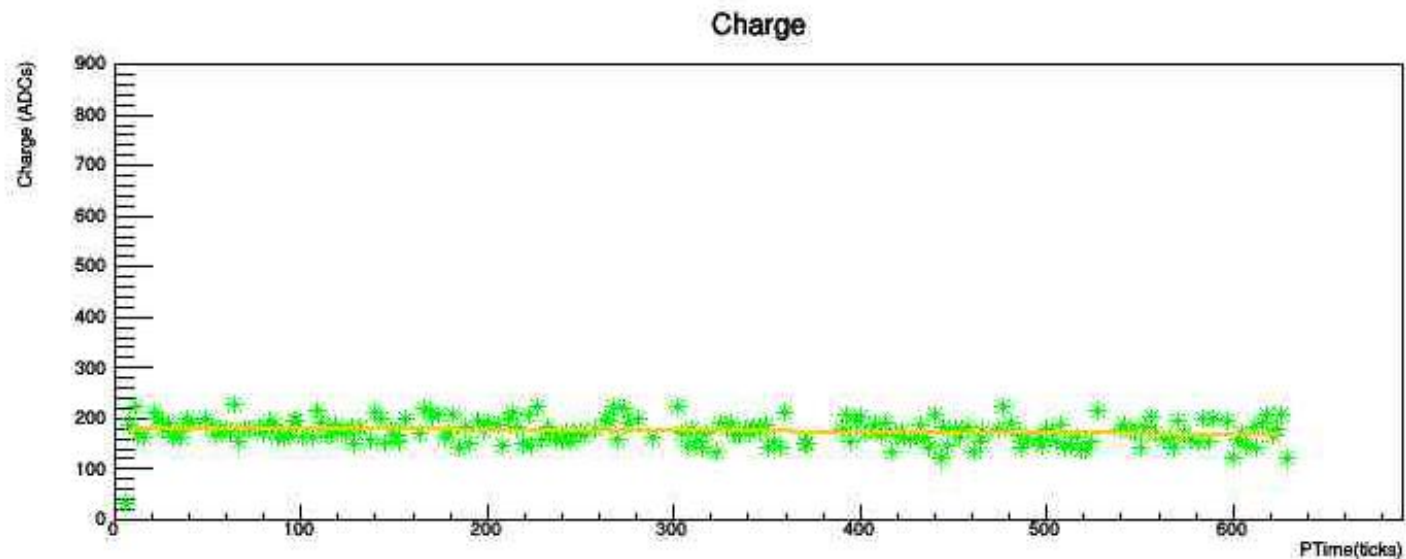
Purity Calculation cont.

- Create histogram of difference between fit and data
 - Fit with Landau function to get sigma



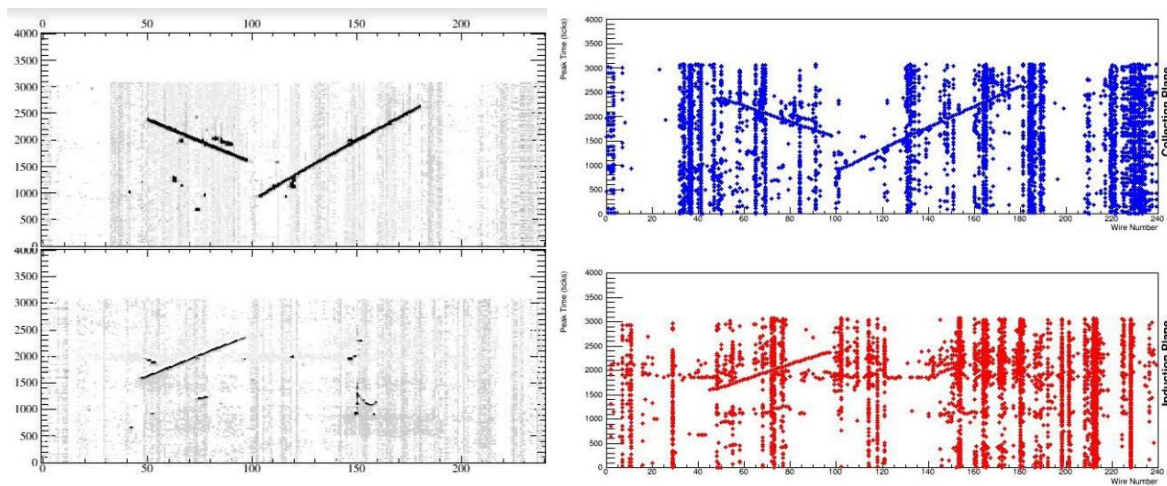
Purity Calculation cont.

- Refit with sigma cuts
 - Keep values and store into file that is used as input for a minimizer of a maximum likelihood estimator (MLE)
 - Lifetime is extracted



Event Display

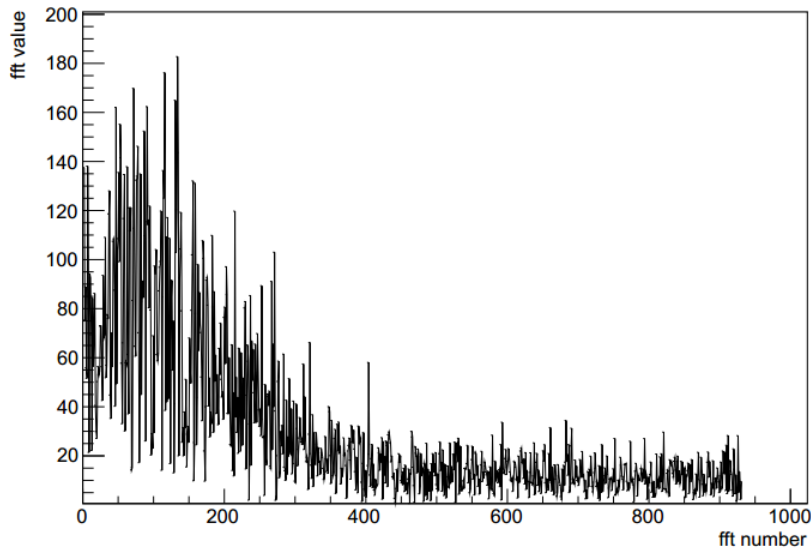
- Current event display works great
 - However, is loaded with features
 - Using for small checkups such as thresholds is slow
 - For changing Collection and Induction planes separately
- Created a fast Event display that uses the output of Purity.cc
 - “Lite version”
 - Fast and reliable



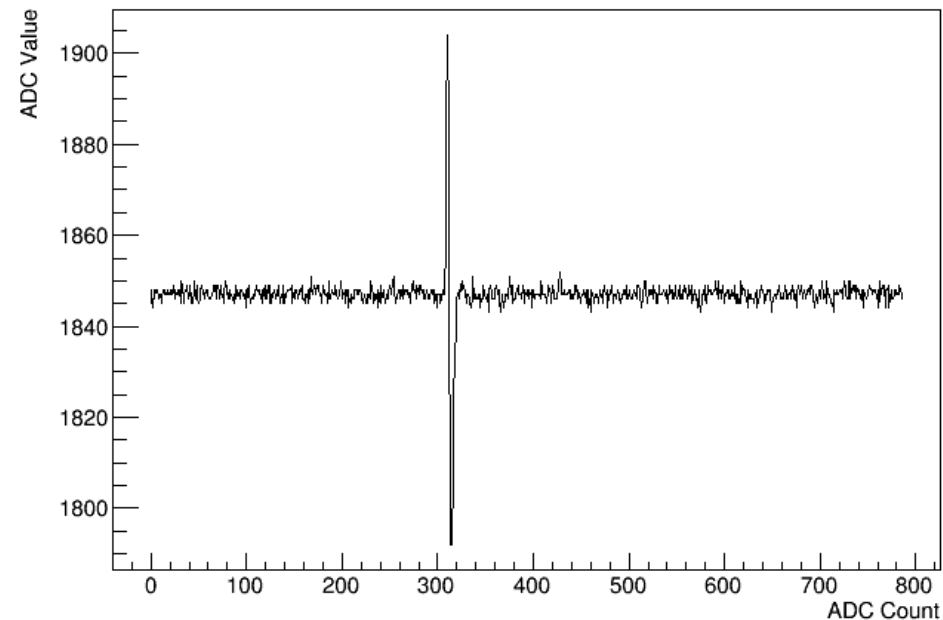
Multi-Channel Analysis

- Current Plotting scripts analysis works
 - However, per event and per channel basis
- Need a script to gather all of the channel data to analyze on an event basis
 - FFT and waveform plotting

Event 0 Channel 0 FFT

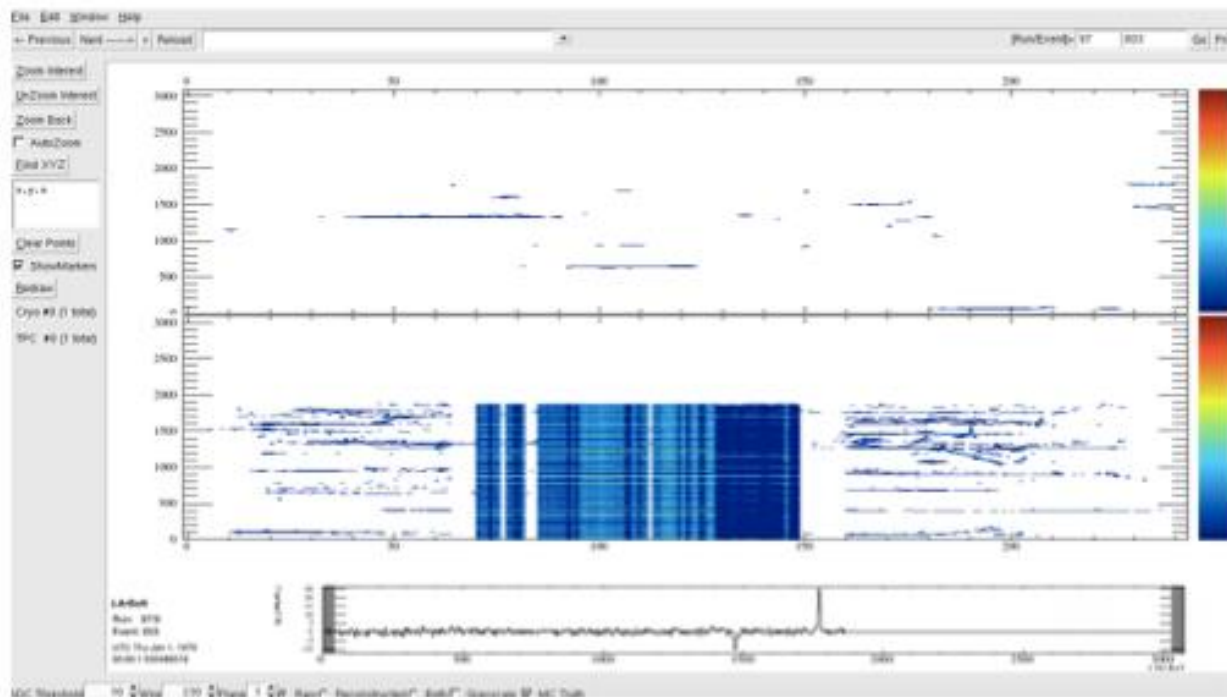


Event 0 Channel 120 Waveform



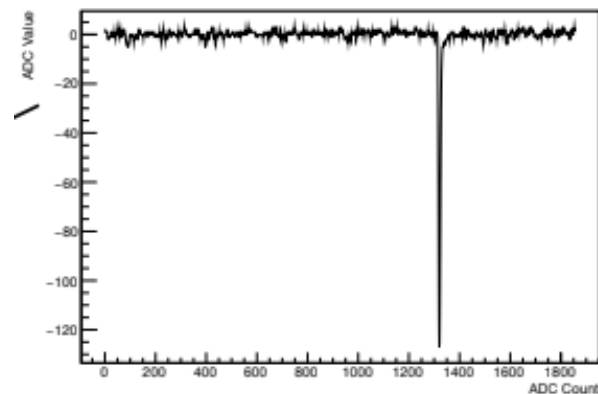
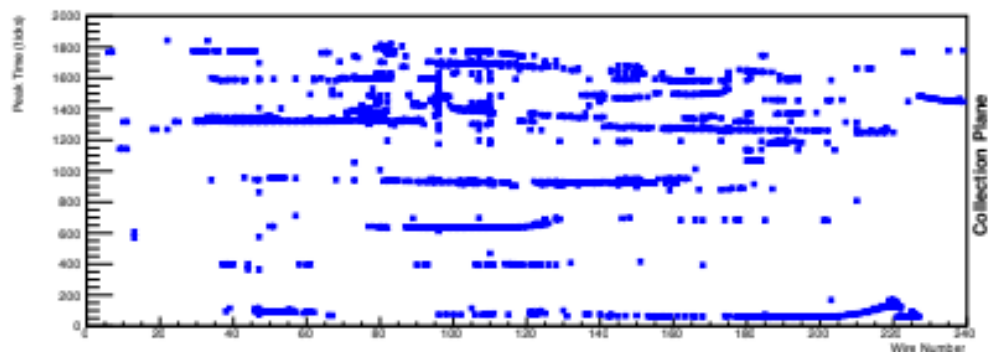
Data

- Data was not correct
- Malfunction in wires
 - Collection had inverted peaks
 - Induction had noisy wires and a broken motherboard

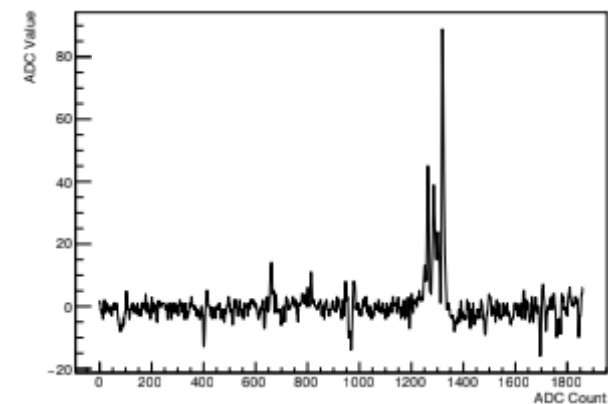
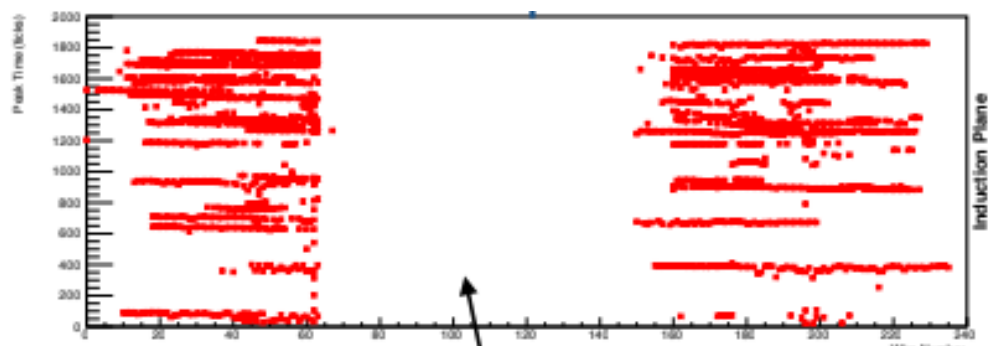


Data cont.

Collection Plane

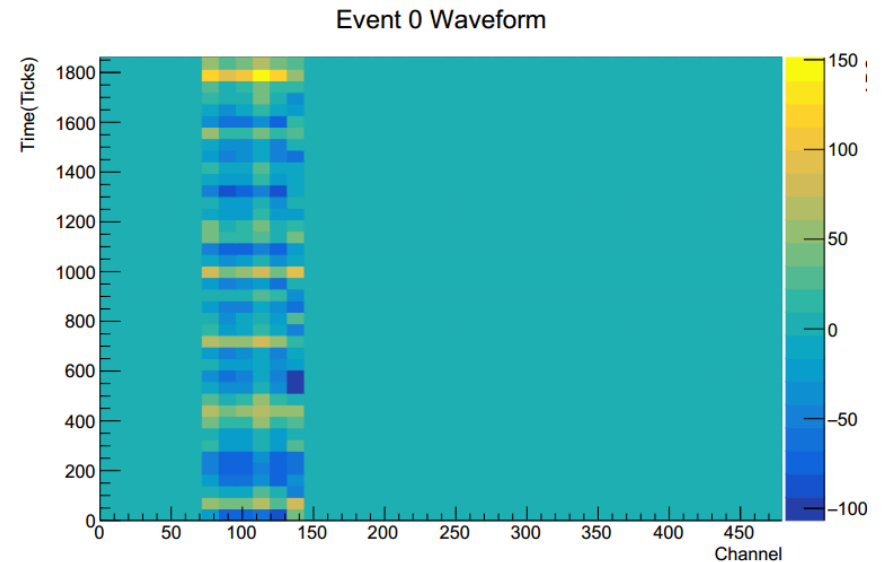
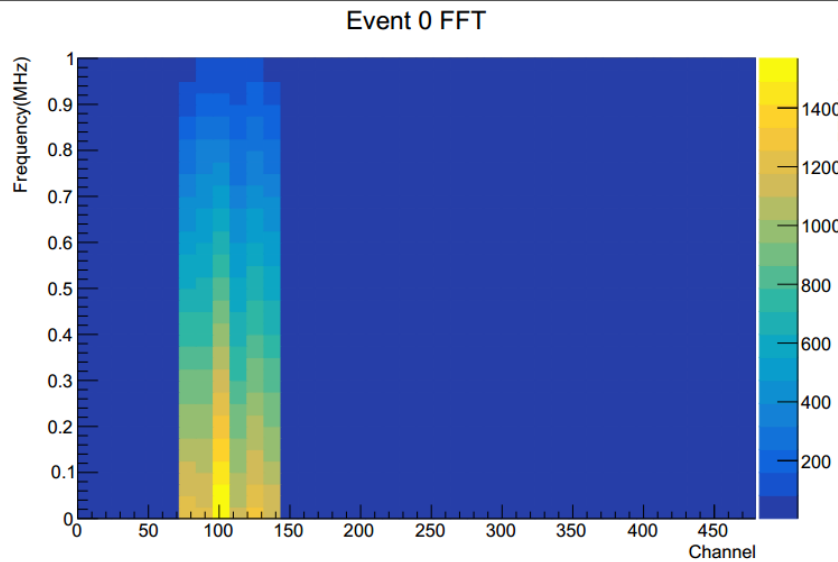


Induction Plane



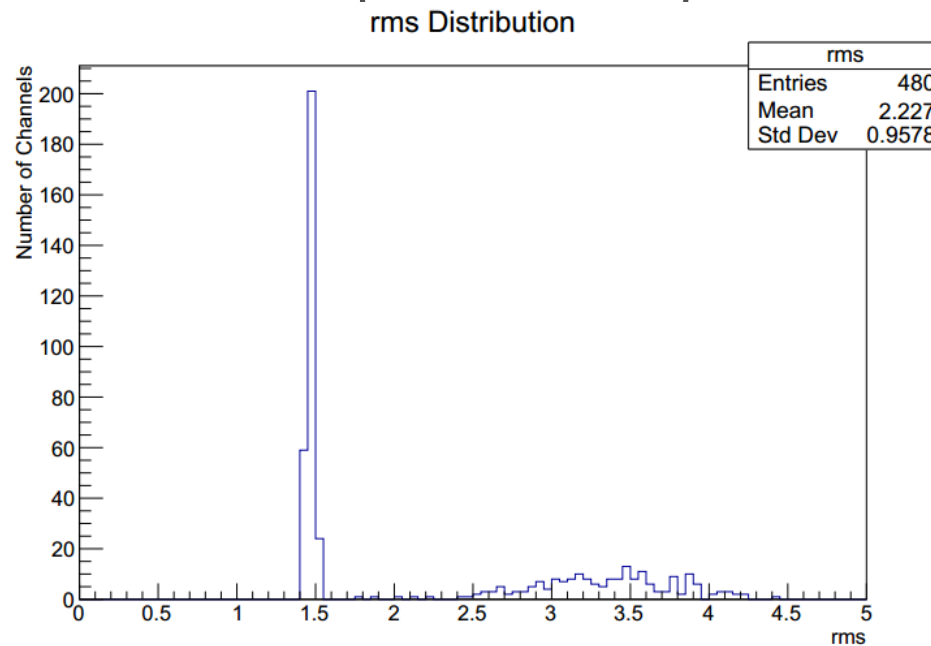
Ignored because
of high noise

Multi-Channel Analysis cont.

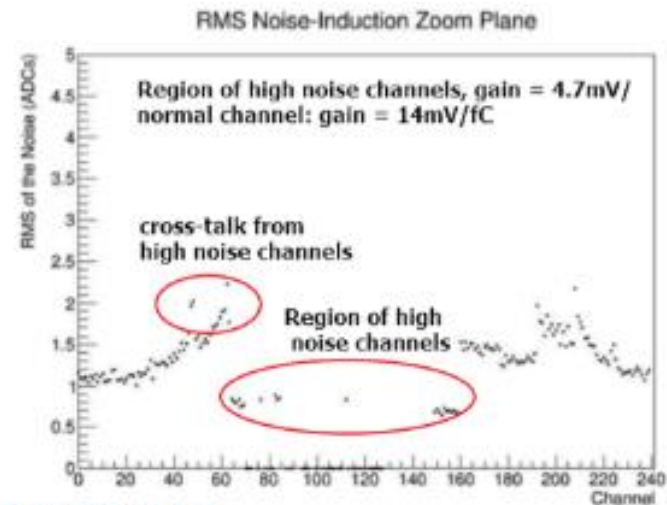
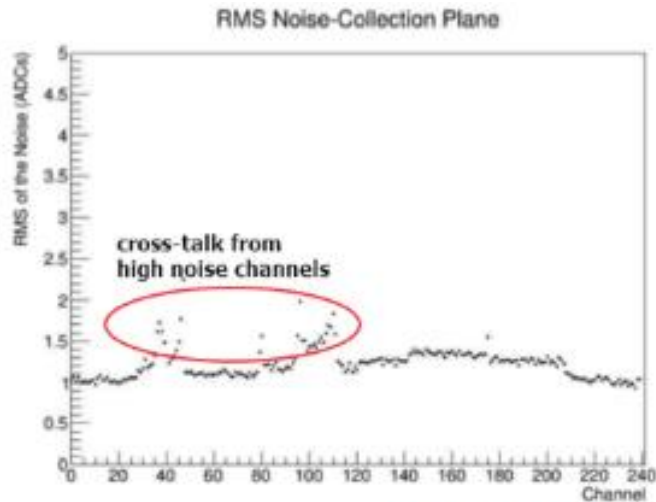


Noise RMS

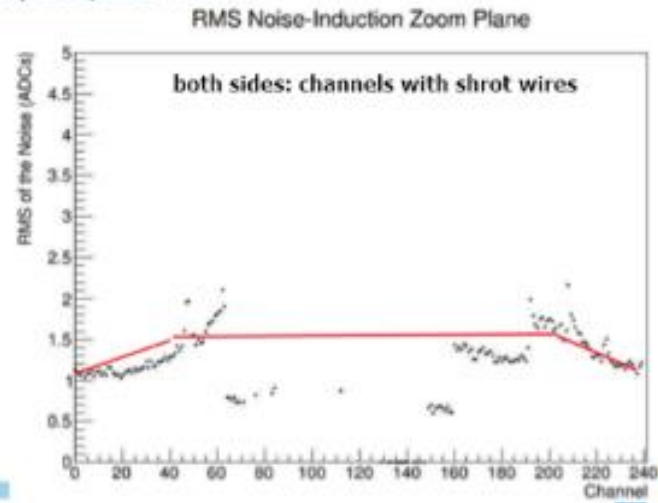
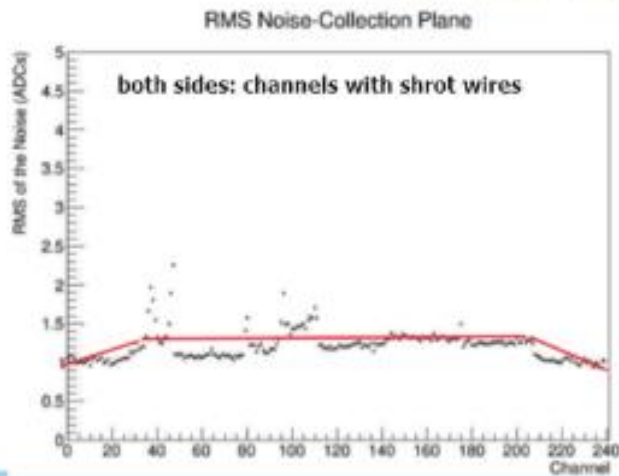
- From the purity calculation, values away from the linear fit are used to calculate the RMS of the noise
- Currently exits on an event basis
 - Now averages over the entire set of events in a file
 - Induction and Collection plane are separate



RMS Plots



Run 139 from 07/03/2018



Results

- Purity is added to framework
 - Part of VST git repository
- Noise RMS is finished
 - Useful for analyzing the channels
 - Pinpointing bad channels
- FFT & Waveform vs Channel is finished
 - Part of VSTAnalysis git repository
- Event display is done
 - Operates as long as Purity.cc operates

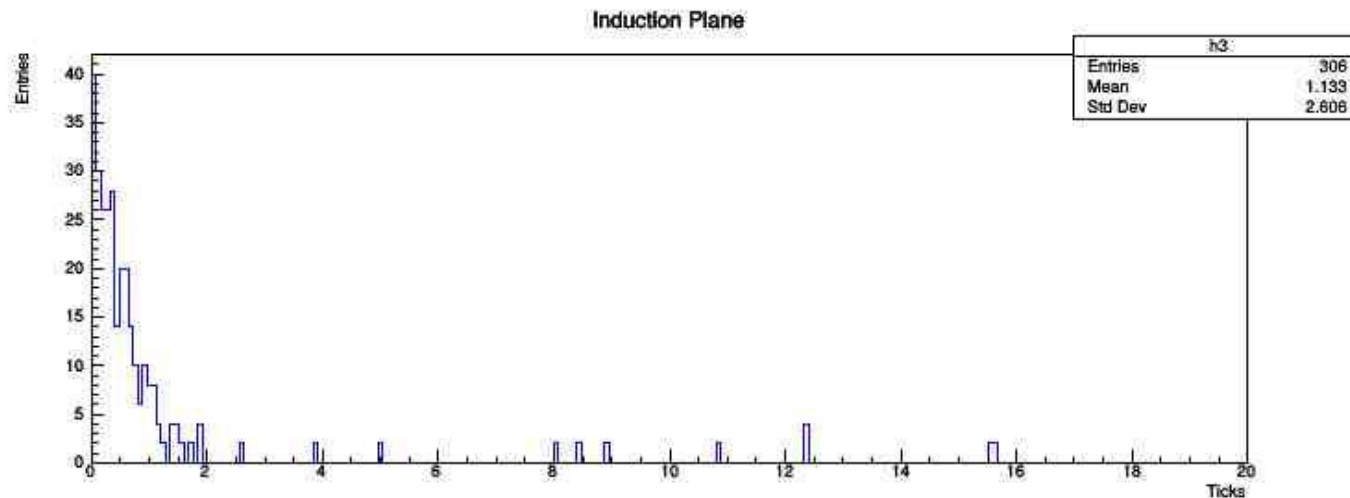
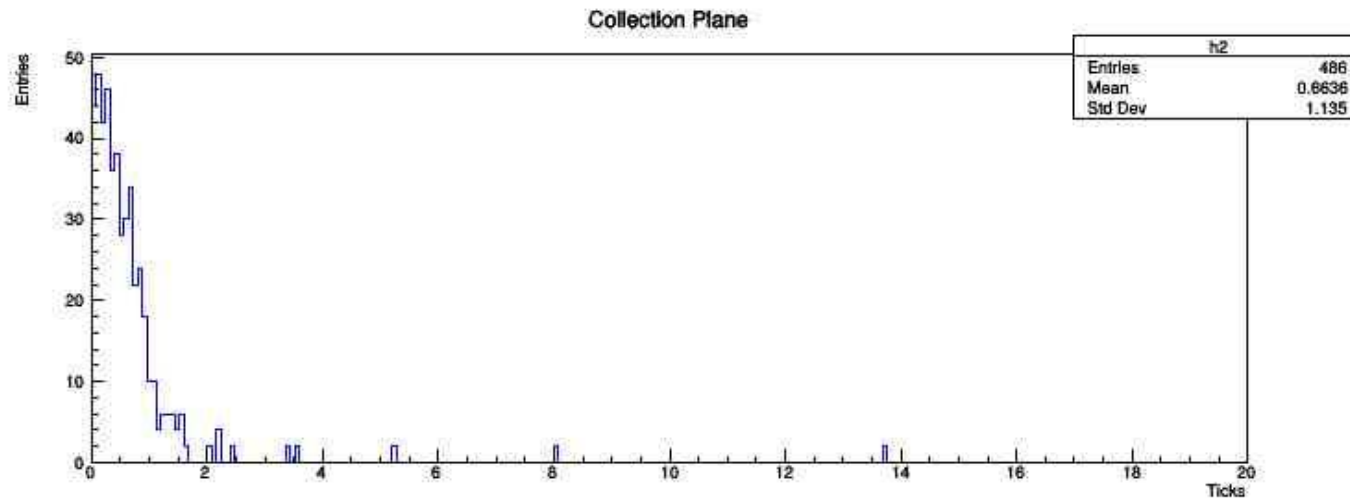
Future Work

- Tune the Purity.cc code for data from simulation
 - Modifying “sigma” cuts
- RMS used to set threshold based on the event
 - To eliminate general settings
- Finalize a script for analyzing the general trend of lifetimes

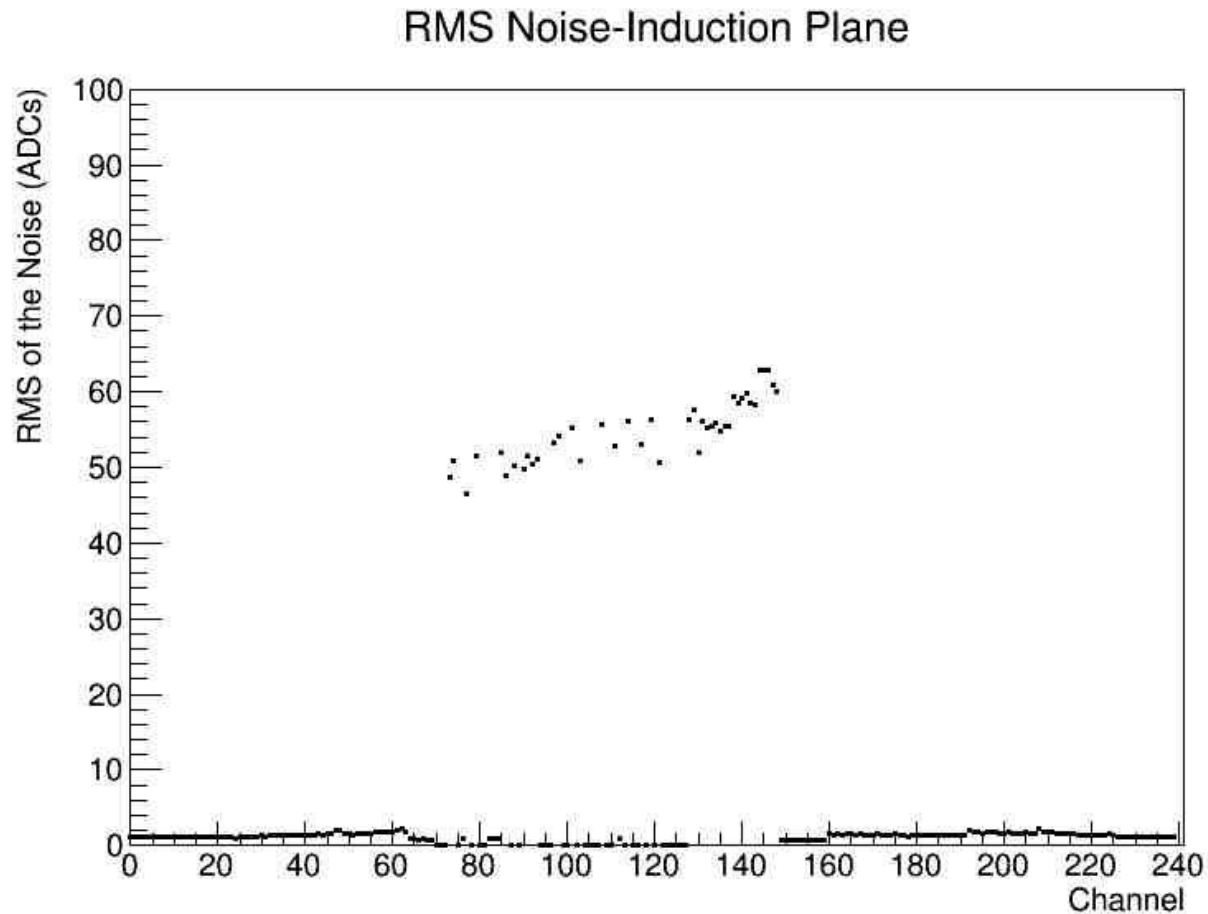
Acknowledgments

- I would like to thank the following people for their patience and help as they were always available to answer my many questions.
 - Minerba, Gray, Thomas, Dominic
- Thank you to my Fermilab mentors for helping me with general work at Fermi and with my education path
 - Donovan, Javier, and Elliot
- Finally, I would also like to thank Fermilab and the SIST committee, for such an amazing summer experience
 - Sandra, Judy, Laura

Distance from linear fit

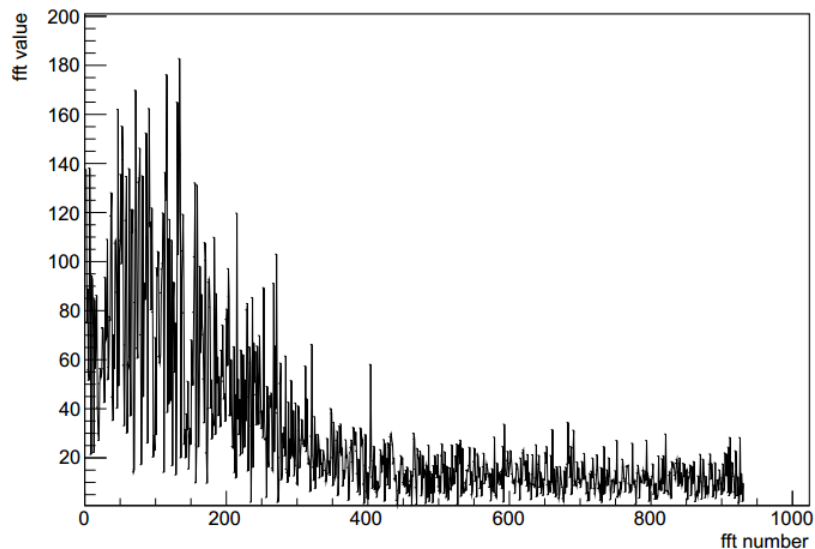


Data Induction Plane Noise

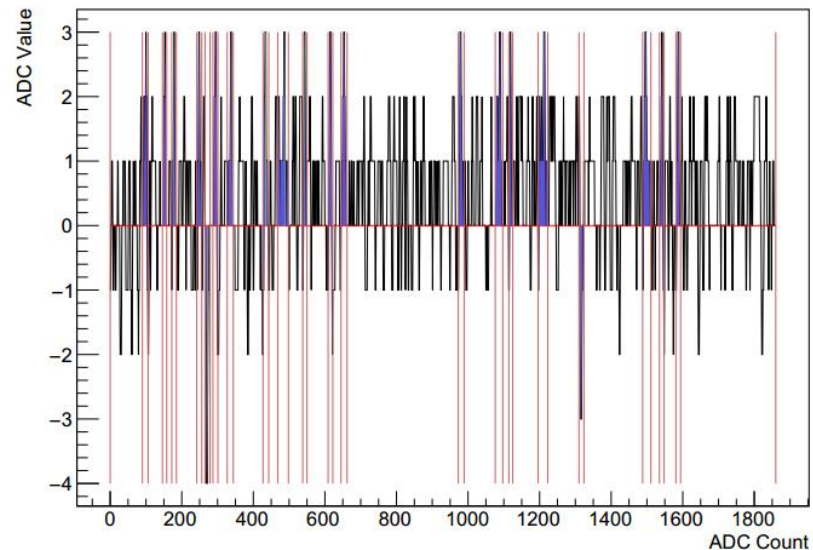


Data analysis

Event 0 Channel 0 FFT



Event 0 Channel 0 Waveform



Beam Composition

